# **Dual Line CAN Bus Protector**

The SZ/NUP2105L has been designed to protect the CAN transceiver in high-speed and fault tolerant networks from ESD and other harmful transient voltage events. This device provides bidirectional protection for each data line with a single compact SOT-23 package, giving the system designer a low cost option for improving system reliability and meeting stringent EMI requirements.

#### **Features**

- 350 W Peak Power Dissipation per Line (8 x 20 usec Waveform)
- Low Reverse Leakage Current (< 100 nA)
- Low Capacitance High-Speed CAN Data Rates
- IEC Compatibility: IEC 61000-4-2 (ESD): Level 4
  - IEC 61000-4-4 (EFT): 40 A 5/50 ns
  - IEC 61000-4-5 (Lighting) 8.0 A (8/20 µs)
- ISO 7637-1, Nonrepetitive EMI Surge Pulse 2, 9.5 A (1 x 50 μs)
- ISO 7637–3, Repetitive Electrical Fast Transient (EFT) EMI Surge Pulses, 50 A (5 x 50 ns)
- Flammability Rating UL 94 V-0
- AEC-Q101 Qualified and PPAP Capable
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements
- Pb-Free Packages are Available\*

#### **Applications**

- Industrial Control Networks
  - ◆ Smart Distribution Systems (SDS®)
  - ♦ DeviceNet™
- Automotive Networks
  - ◆ Low and High-Speed CAN
  - ♦ Fault Tolerant CAN



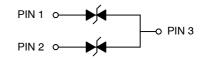
#### ON Semiconductor®

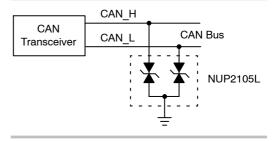
http://onsemi.com

#### SOT-23 DUAL BIDIRECTIONAL VOLTAGE SUPPRESSOR 350 W PEAK POWER



SOT-23 CASE 318 STYLE 27





#### **MARKING DIAGRAM**



27E = Device Code

M = Date Code

Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C, unless otherwise specified)

Symbol	Rating	Value	Unit
PPK	Peak Power Dissipation 8 x 20 μs Double Exponential Waveform (Note 1)	350	W
$T_J$	Operating Junction Temperature Range	-55 to 150	°C
TJ	Storage Temperature Range	-55 to 150	°C
$T_L$	Lead Solder Temperature (10 s)	260	°C
ESD	Human Body model (HBM) Machine Model (MM) IEC 61000-4-2 Specification (Contact)	16 400 30	kV V kV

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

#### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C, unless otherwise specified)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>RWM</sub>	Reverse Working Voltage	(Note 2)	24	-	-	V
V <sub>BR</sub>	Breakdown Voltage	I <sub>T</sub> = 1 mA (Note 3)	26.2	-	32	V
I <sub>R</sub>	Reverse Leakage Current	V <sub>RWM</sub> = 24 V	-	15	100	nA
V <sub>C</sub>	Clamping Voltage	I <sub>PP</sub> = 5 A (8 x 20 μs Waveform) (Note 4)	-	-	40	V
V <sub>C</sub>	Clamping Voltage	I <sub>PP</sub> = 8 A (8 x 20 μs Waveform) (Note 4)	-	-	44	V
I <sub>PP</sub>	Maximum Peak Pulse Current	8 x 20 μs Waveform (Note 4)	-	-	8.0	Α
CJ	Capacitance	V <sub>R</sub> = 0 V, f = 1 MHz (Line to GND)	-	-	30	pF

<sup>2.</sup> TVS devices are normally selected according to the working peak reverse voltage (V<sub>RWM</sub>), which should be equal or greater than the DC or continuous peak operating voltage level.

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>	
NUP2105LT1	SOT-23	3,000 / Tape & Reel	
NUP2105LT1G	SOT-23 (Pb-Free)	3,000 / Tape & Reel	
SZNUP2105LT1G	SOT-23 (Pb-Free)	3,000 / Tape & Reel	
NUP2105LT3	SOT-23	10,000 / Tape & Reel	
NUP2105LT3G	SOT-23 (Pb-Free)	10,000 / Tape & Reel	
SZNUP2105LT3G	SOT-23 (Pb-Free)	10,000 / Tape & Reel	

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

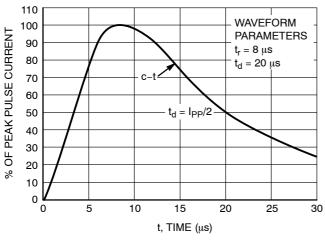
<sup>1.</sup> Non-repetitive current pulse per Figure 1.

<sup>3.</sup> V<sub>BB</sub> is measured at pulse test current I<sub>T</sub>.

<sup>4.</sup> Pulse waveform per Figure 1.

#### TYPICAL PERFORMANCE CURVES

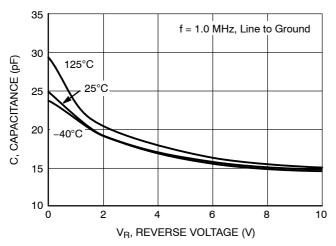
(T<sub>J</sub> = 25°C unless otherwise noted)



12.0 € **PULSE WAVEFORM** IPP, PEAK PULSE CURRENT 8 x 20 μs per Figure 1 10.0 8.0 6.0 4.0 2.0 0.0 35 30 40 45 25 50 V<sub>C</sub>, CLAMPING VOLTAGE (V)

Figure 1. Pulse Waveform, 8  $\times$  20  $\mu$ s

Figure 2. Clamping Voltage vs Peak Pulse Current



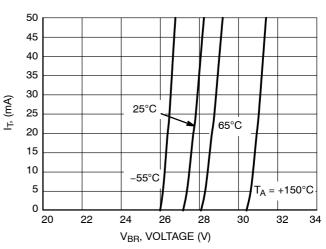
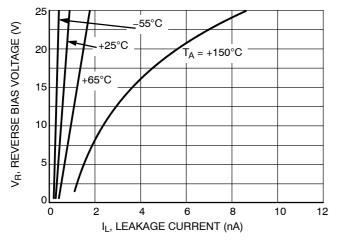


Figure 3. Typical Junction Capacitance vs
Reverse Voltage

Figure 4. V<sub>BR</sub> versus I<sub>T</sub> Characteristics



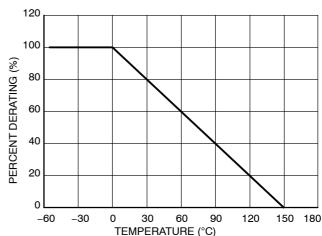


Figure 5. I<sub>R</sub> versus Temperature Characteristics

Figure 6. Temperature Power Dissipation Derating

#### **APPLICATIONS**

#### **Background**

The Controller Area Network (CAN) is a serial communication protocol designed for providing reliable high speed data transmission in harsh environments. TVS diodes provide a low cost solution to conducted and radiated Electromagnetic Interference (EMI) and Electrostatic Discharge (ESD) noise problems. The noise immunity level and reliability of CAN transceivers can be easily increased by adding external TVS diodes to prevent transient voltage failures.

The NUP2105L provides a transient voltage suppression solution for CAN data communication lines. The NUP2105L is a dual bidirectional TVS device in a compact SOT-23 package. This device is based on Zener technology that optimizes the active area of a PN junction to provide robust protection against transient EMI surge voltage and

ESD. The NUP2105L has been tested to EMI and ESD levels that exceed the specifications of popular high speed CAN networks.

#### **CAN Physical Layer Requirements**

Table 1 provides a summary of the system requirements for a CAN transceiver. The ISO 11898–2 physical layer specification forms the baseline for most CAN systems. The transceiver requirements for the Honeywell<sup>®</sup> Smart Distribution Systems (SDS<sup>®</sup>) and Rockwell (Allen–Bradley) DeviceNet<sup>™</sup> high speed CAN networks are similar to ISO 11898–2. The SDS and DeviceNet transceiver requirements are similar to ISO 11898–2; however, they include minor modifications required in an industrial environment.

Table 1. Transceiver Requirements for High-Speed CAN Networks

Parameter	ISO 11898-2	SDS Physical Layer Specification 2.0	DeviceNet
Min / Max Bus Voltage (12 V System)	-3.0 V / 16 V	11 V / 25 V	Same as ISO 11898-2
Common Mode Bus Voltage	CAN_L:	Same as ISO 11898-2	Same as ISO 11898-2
Transmission Speed	1.0 Mb/s @ 40 m 125 kb/s @ 500 m	Same as ISO 11898-2	500 kb/s @ 100 m 125 kb/s @ 500 m
Not specified, recomme ≥ ±8.0 kV (contact)		Not specified, recommended ≥ ±8.0 kV (contact)	Not specified, recommended ≥ ±8.0 kV (contact)
EMI Immunity	ISO 7637-3, pulses 'a' and 'b'	IEC 61000-4-4 EFT	Same as ISO 11898-2
Popular Applications	Automotive, Truck, Medical and Marine Systems	Industrial Control Systems	Industrial Control Systems

#### **EMI Specifications**

The EMI protection level provided by the TVS device can be measured using the International Organization for Standardization (ISO) 7637–1 and –3 specifications that are representative of various noise sources. The ISO 7637–1 specification is used to define the susceptibility to coupled transient noise on a 12 V power supply, while ISO 7637–3 defines the noise immunity tests for data lines. The ISO 7637 tests also verify the robustness and reliability of a design by applying the surge voltage for extended durations.

The IEC 61000-4-X specifications can also be used to quantify the EMI immunity level of a CAN system. The IEC

61000–4 and ISO 7637 tests are similar; however, the IEC standard was created as a generic test for any electronic system, while the ISO 7637 standard was designed for vehicular applications. The IEC61000–4–4 Electrical Fast Transient (EFT) specification is similar to the ISO 7637–1 pulse 1 and 2 tests and is a requirement of SDS CAN systems. The IEC 61000–4–5 test is used to define the power absorption capacity of a TVS device and long duration voltage transients such as lightning. Table 2 provides a summary of the ISO 7637 and IEC 61000–4–X test specifications. Table 3 provides the NUP2105L's ESD test results.

Table 2. ISO 7637 and IEC 61000-4-X Test Specifications

Test	Waveform	Test Specifications	NUP2105L Test	Simulated Noise Source
ISO 7637-1	Pulse 1	V <sub>s</sub> = 0 to -100 V I <sub>max</sub> = 10 A t <sub>duration</sub> = 5000 pulses	$\begin{split} I_{max} &= 1.75 \text{ A} \\ V_{clamp\_max} &= 31 \text{ V} \\ t_{duration} &= 5000 \text{ pulses} \\ R_i &= 10  \Omega, t_r = 1.0  \mu\text{s}, \\ t_{d\_10\%} &= 2000  \mu\text{s}, t_1 = 2.5 \text{ s}, \\ \overline{t}_2 &= 200 \text{ ms}, t_3 = 100  \mu\text{s} \end{split}$	DUT in parallel with inductive load that is disconnected from power supply.
12 V Power Supply Lines	Pulse 2	V <sub>s</sub> = 0 to +100 V I <sub>max</sub> = 10 A t <sub>duration</sub> = 5000 pulses	$\begin{split} I_{max} &= 9.5 \text{ A} \\ V_{clamp\_max} &= 33 \text{ V} \\ t_{duration} &= 5000 \text{ pulses} \\ \text{Ri} &= 10 \Omega,  t_{r} = 1.0 \mu\text{s}, \\ t_{d\_10\%} &= 50 \mu\text{s},  t_{1} = 2.5 \text{ s}, \\ t_{2} &= 200 \text{ ms} \end{split}$	DUT in series with inductor that is disconnected.
ISO 7637-3	Pulse 'a'	$V_s = -60 \text{ V}$ $I_{max} = 1.2 \text{ A}$	I <sub>max</sub> = 50 A V <sub>clamp_max</sub> = 40 V t <sub>duration</sub> = 60 minutes	Switching noise of inductive loads.
Data Line EFT	Pulse 'b'	$t_{duration} = 10 \text{ minutes}$ $V_{s} = +40 \text{ V}$ $I_{max} = 0.8 \text{ A}$ $t_{duration} = 10 \text{ minutes}$	$R_i = 50 \ \Omega,  t_r = 5.0 \ \text{ns}, \\ t_{d\_10\%} = 0.1 \ \text{ms},  t_1 = 100 \ \mu\text{s}, \\ t_2 = 10 \ \text{ms},  t_3 = 90 \ \text{ms}$	
IEC 61000-4-4 Data Line EFT		$V_{\text{open circuit}} = 2.0 \text{ kV}$ $I_{\text{short circuit}} = 40 \text{ A}$ $(\text{Level 4} = \text{Severe Industrial}$ $Environment)$ $R_{i} = 50 \ \Omega, \ t_{r} < 5.0 \ \text{ns},$ $t_{d}_{50\%} = 50 \ \text{ns}, \ t_{\text{burst}} = 15 \ \text{ms},$ $f_{\text{burst}} = 2.0 \ \text{to } 5.0 \ \text{kHz},$ $t_{\text{repeat}} = 300 \ \text{ms}$ $t_{\text{duration}} = 1 \ \text{minute}$	(Note 2)	Switching noise of inductive loads.
IEC 61000-4-5		$V_{open\ circuit}$ = 1.2 x 50 μs, $I_{short\ circuit}$ = 8 x 20 μs $R_i$ = 50 $\Omega$		Lightning, nonrepetitive power line and load switching

<sup>1.</sup> DUT = device under test.

Table 3. NUP2105L ESD Test Results

ESD Specification	Test	Test Level	Pass / Fail
Human Body Model	Contact	16 kV	Pass
	Contact	30 kV (Note 3)	Pass
IEC 61000-4-2	Non-contact (Air Discharge)	30 kV (Note 3)	Pass

<sup>3.</sup> Test equipment maximum test voltage is 30 kV.

<sup>2.</sup> The EFT immunity level was measured with test limits beyond the IEC 61000-4-4 test, but with the more severe test conditions of ISO 7637-3.

#### **TVS Diode Protection Circuit**

TVS diodes provide protection to a transceiver by clamping a surge voltage to a safe level. TVS diodes have high impedance below and low impedance above their breakdown voltage. A TVS Zener diode has its junction optimized to absorb the high peak energy of a transient event, while a standard Zener diode is designed and specified to clamp a steady state voltage.

Figure 7 provides an example of a dual bidirectional TVS diode array that can be used for protection with the high-speed CAN network. The bidirectional array is created from four identical Zener TVS diodes. The clamping voltage of the composite device is equal to the breakdown

voltage of the diode that is reversed biased, plus the diode drop of the second diode that is forwarded biased.

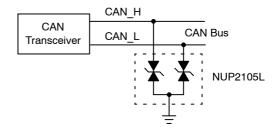
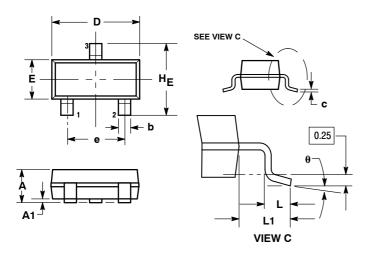


Figure 7. High-Speed and Fault Tolerant CAN TVS
Protection Circuit

#### PACKAGE DIMENSIONS

SOT-23 (TO-236) CASE 318-08 **ISSUE AP** 



#### NOTES:

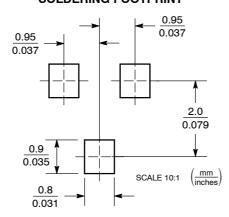
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH
- MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.89	1.00	1.11	0.035	0.040	0.044
A1	0.01	0.06	0.10	0.001	0.002	0.004
b	0.37	0.44	0.50	0.015	0.018	0.020
С	0.09	0.13	0.18	0.003	0.005	0.007
D	2.80	2.90	3.04	0.110	0.114	0.120
E	1.20	1.30	1.40	0.047	0.051	0.055
е	1.78	1.90	2.04	0.070	0.075	0.081
L	0.10	0.20	0.30	0.004	0.008	0.012
L1	0.35	0.54	0.69	0.014	0.021	0.029
HE	2.10	2.40	2.64	0.083	0.094	0.104
θ	0°		10°	0°		10°

STYLE 27: PIN 1. CATHODE

2. CATHODE 3. CATHODE

#### **SOLDERING FOOTPRINT**



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